

Topography and localized charge of steps on CeO₂(111) investigated by AFM/KPFM

Xiaosen Ren^{1,2,3}, Pengli Shu^{1,2,3}, Ketong Zhang^{1,2,3}, Jiuyan Wei^{1,2,3}, Qiang Zhu^{1,2,3}, Huanfei Wen^{1,2}, Yasuhiro Sugawara^{3,4}, Yanjun Li^{3,4}, Jun Tang^{1,2,3}, Zongmin Ma^{1,2,3*} and Jun Liu^{1,2,3*}

¹State Key Laboratory of Widegap Semiconductor Optoelectronic Materials and Technologies, North University of China, Taiyuan, Shanxi, 030051, China

²State key Laboratory of Extreme Environment Optoelectronic Dynamic Measurement Technology and Instrument, Taiyuan, Shanxi, 030051, China

³School of Semiconductor and Physics, North University of China, Taiyuan, Shanxi, 030051, China

⁴Department of Applied Physics, Graduate School of Engineering, Osaka University, 2-1 Yamadaoka, Suita, Osaka 565-0871, Japan

Presenting author's e-mail:mzmncit@163.com

The configuration of step edges on metal oxide surface is significant for understanding fundamental reactivity and predicting the performance in catalysis. In this work, the topography feature and charge of steps on CeO₂(111) are investigated by atomic force microscopy /kelvin probe force microscopy combined with density functional theory. Hexagonal islands and pits containing step I edge and step II edge have been observed at annealing 1100 K. The irregular structures with the addition of step III edge have been found at 1200 K. The measurement of contact potential difference reveals that step II displays the strongest localized charge state, followed by step III, and step I with the weakest localized charge state. The calculations of density functional theory have confirmed that step II possesses a stronger localized charge state. In addition, the Ce atoms at the step II edge exhibit greater positive and negative charge accumulation. These results provide the surface structure and electrical potential of three step edges on the CeO₂(111), and establish both experimental and theoretical foundations for subsequent investigations on adsorption and catalysis.

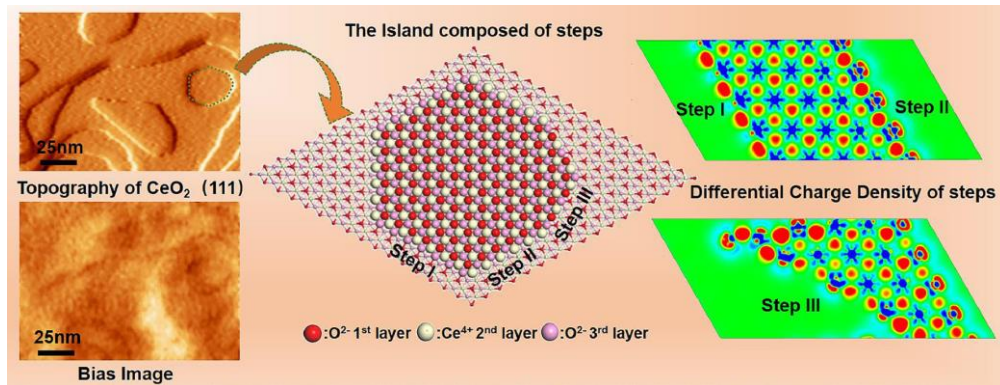


Figure 1. Topography and bias image of CeO₂ (111) surface by NC-AFM/KPFM at 1200 K. The scale mode corresponding to the island of CeO₂ (111) surface and deformation charge density of step I, II and III.

Reference

[1] Pengli. Shu, et al. Surfaces and Interfaces, 51, 104738(2024).